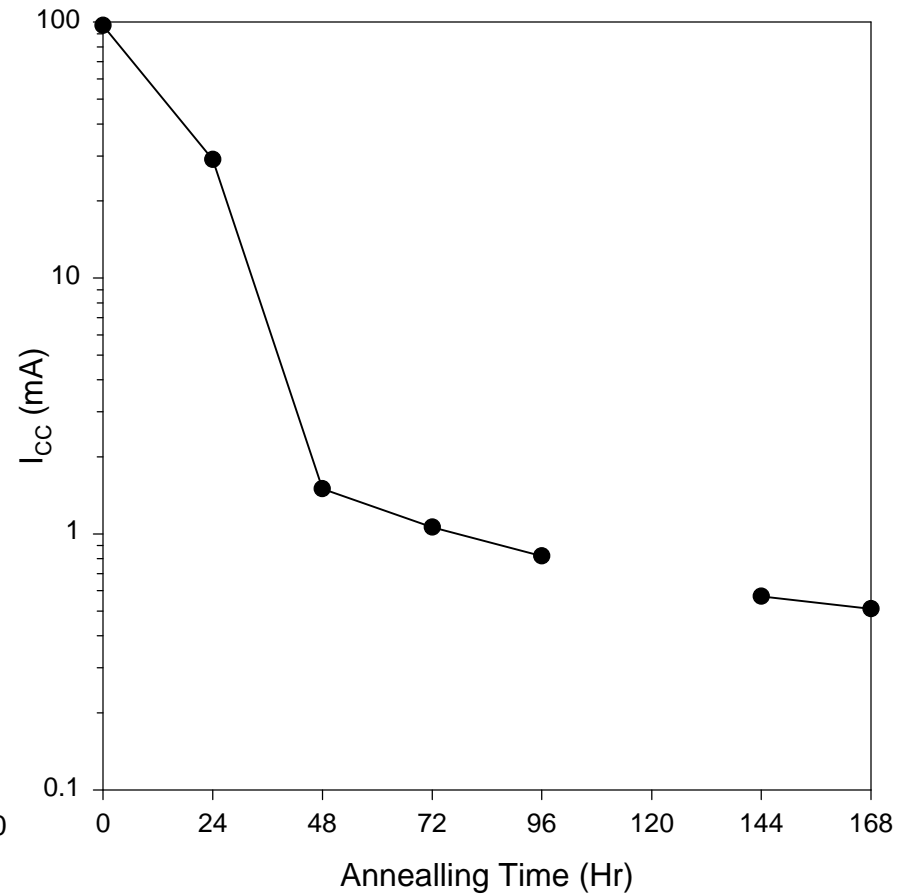
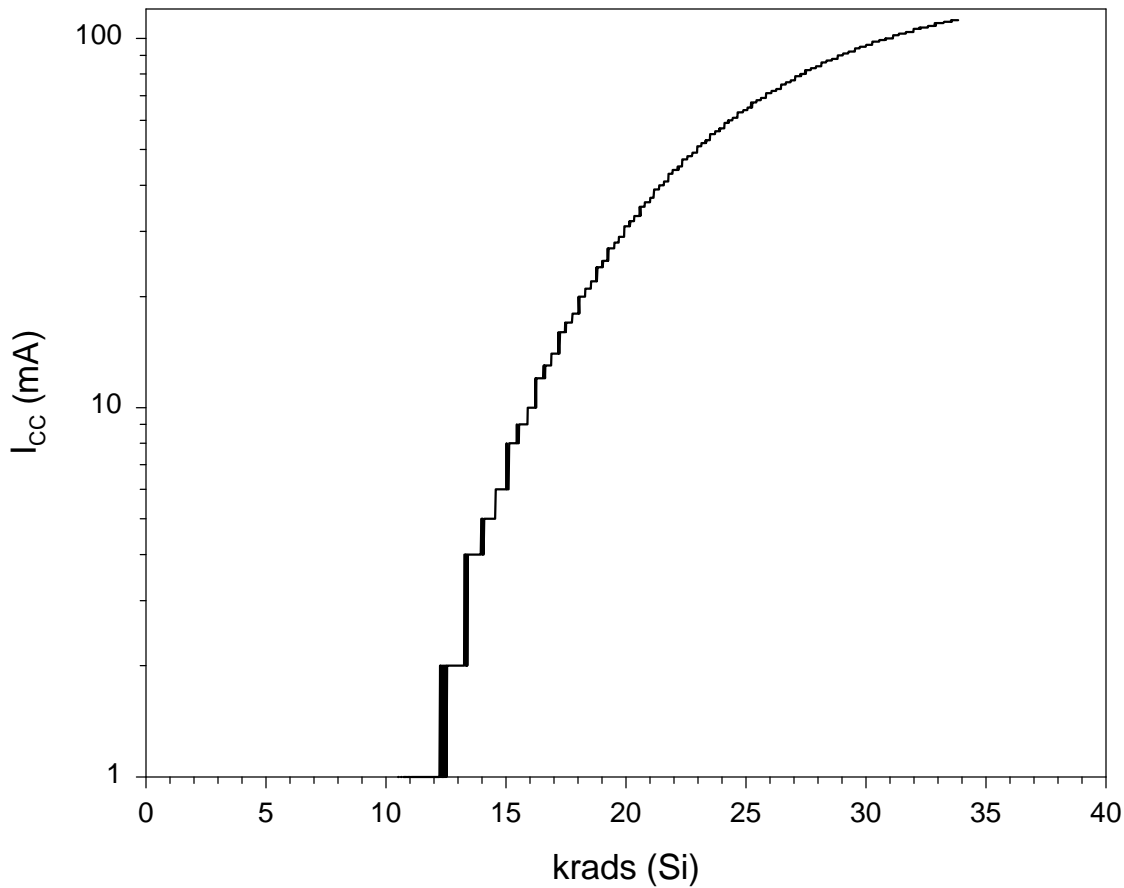


EO-1 A14100A/MEC TID Test  
D/C 9712  
UCL046  
January 5, 1997  
NASA/GSFC  
5 krads(Si)/Day

100C Annealing Data  
January 12, 1998  
NASA/GSFC



NOTE: The logic threshold had a slight increase of approximately 100 mV after irradiation - it decreased approximately 50 mV after the 168 hour, 100C anneal. Values ranged from 1.19V to 1.29V.